

Search Notes



Application/Control No.

10/634,747

Examiner

Dinh Q. Nguyen

Applicant(s)/Patent under
Reexamination

SESSER ET AL.

Art Unit

3752

SEARCHED

Class	Subclass	Date	Examiner
239	204		
	214.17		
	214.19		
	214.23		
	222.11		
	222.15		
	222.17		
	232		
	233		
	243		
	244		
	245		
	246		
	247	3-21-05	DN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
PAST SEARCH ATTACHED REF 09/818, 275 10/119, 294	3-21-05	DN